

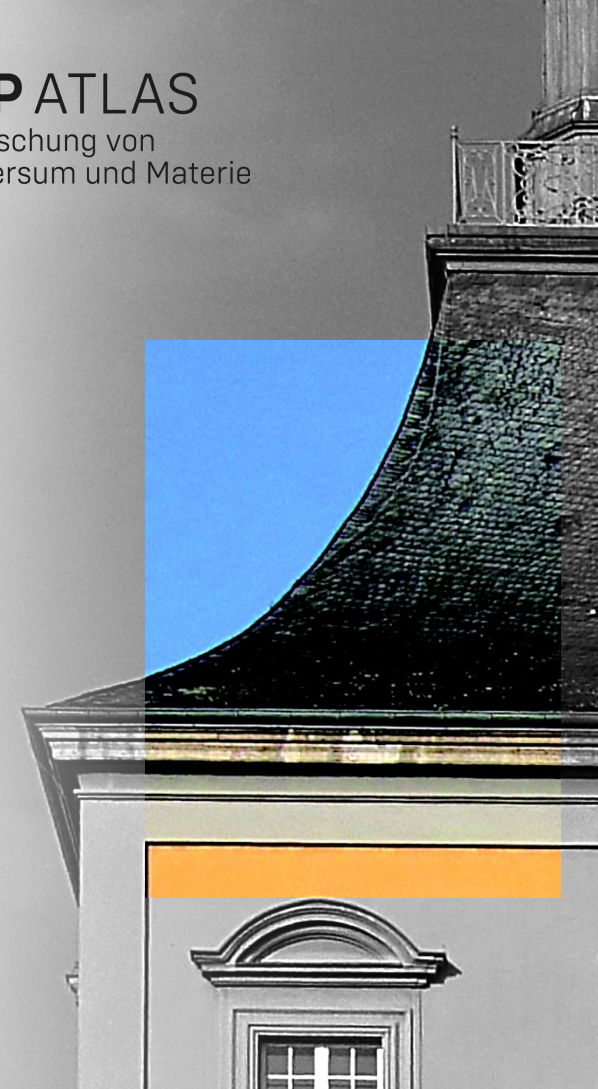
# A PROTON IRRADIATION SITE FOR SILICON DETECTORS AT BONN UNIVERSITY

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DPG Frühjahrstagung 2022, Heidelberg, T13: Semiconductor Detectors

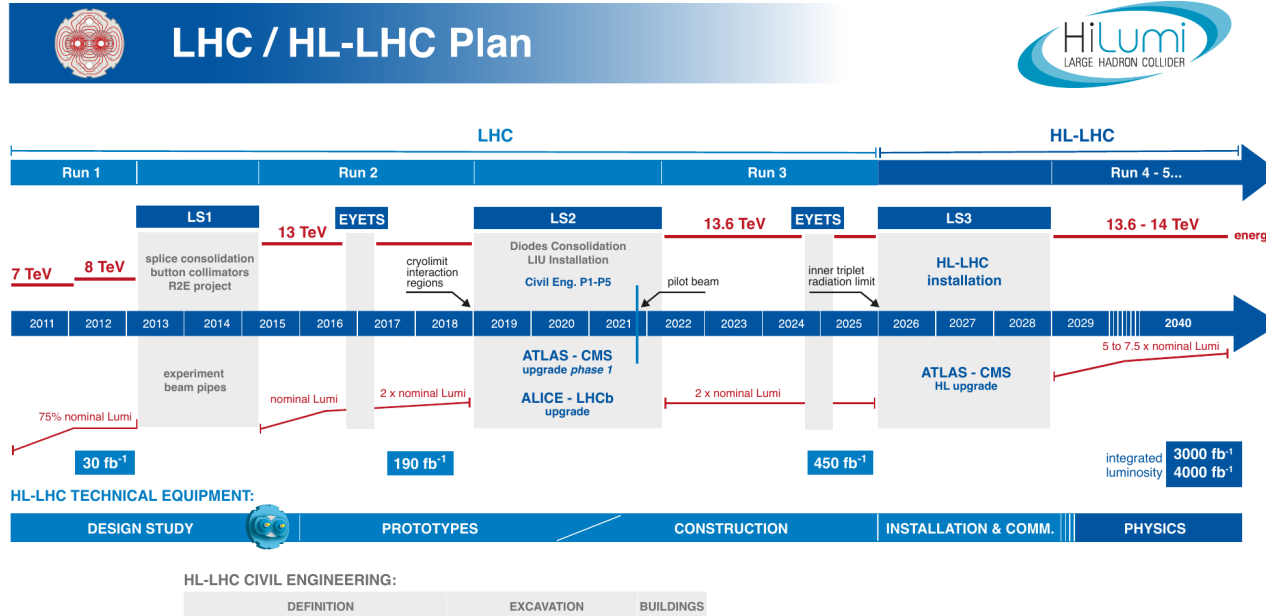
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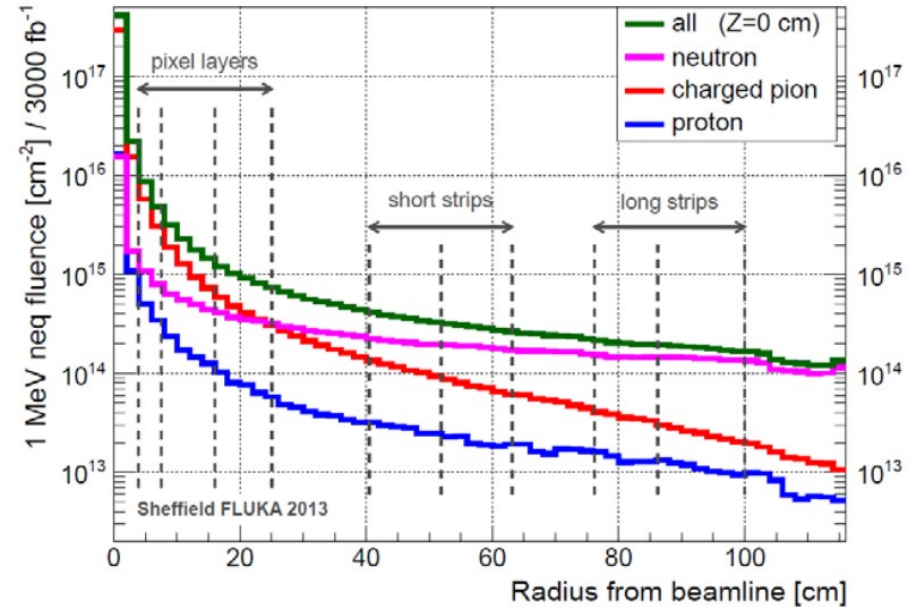
# MOTIVATION



<https://hilumilhc.web.cern.ch/article/l33-schedule-change>

# MOTIVATION

- Estimated radiation levels for ITK after  $3000 \text{ fb}^{-1}$  scaled to 1-MeV neutron equivalent fluence  $n_{\text{eq}}$ :
  - Pixels @ 4 cm  $\approx 1.5 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$
- Si-sensors suffer from **radiation damage**:
  - + Leakage current (+ Noise, + Power)
  - Sensitive volume (- Signal)
  - + Trapping (- Signal)
- Radiation damage studies needed to probe requirements
  - NIEL scaling allows usage of accelerators
  - End-of-Life damage can be induced within O(hours)

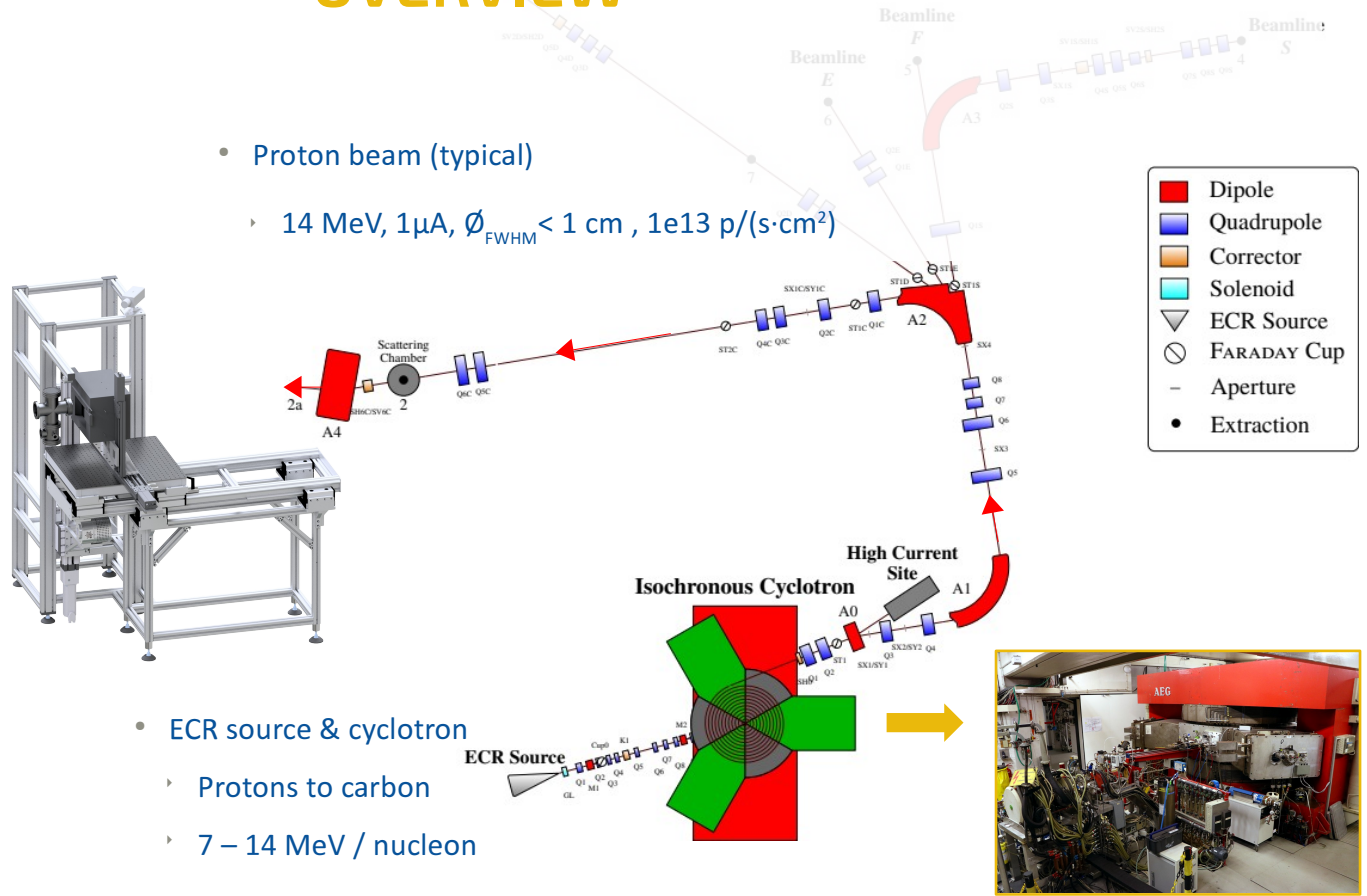


*P. S. Miyagawa and I. Dawson, "Radiation background studies for the phase ii inner tracker upgrade," CERN, Tech. Rep. ATL-UPGRADE-PUB-2014-003, Sep. 2014.*

# OVERVIEW

- Setup
- Diagnostics
- Irradiation
- Proton NIEL
- Conclusion

- Proton beam (typical)
  - 14 MeV, 1μA,  $\varnothing_{FWHM} < 1 \text{ cm}$ ,  $1e13 \text{ p/(s}\cdot\text{cm}^2)$



- ECR source & cyclotron
  - Protons to carbon
  - 7 – 14 MeV / nucleon

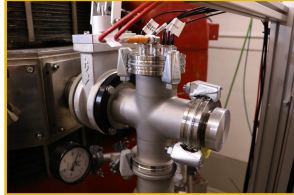


# IRRADIATION SITE

## --SETUP--

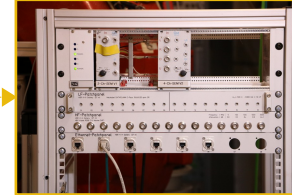
- Calibrated, online beam monitor

- Beam parameter meas. at extraction
- Crucial for **fluence measurement**



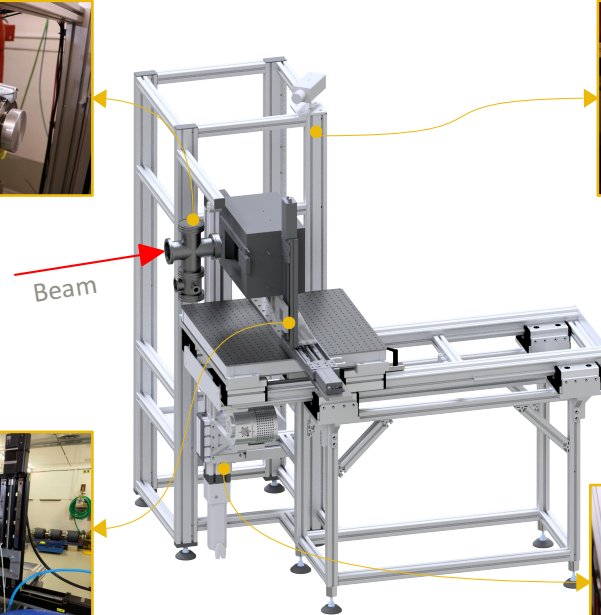
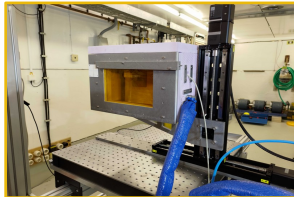
- 19" rack w/ interfaces to setup and R/O

- Interface DUT, lab devices provide custom signals
- Connection to DAQ



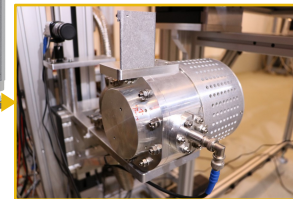
- Insulated DUT box on 2D motorstage

- Houses DUT @  $< -20\text{ °C}$
- 19x11 cm<sup>2</sup> max. DUT size
- Interface for powering, R/O during irradiation



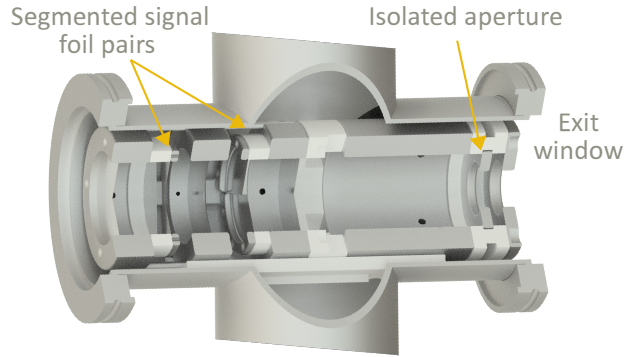
- Faraday cup (FC) with screen on motorstage

- Destructive beam current measurement. at DUT position
- Visual inspection of beam
- Calibrating beam monitor



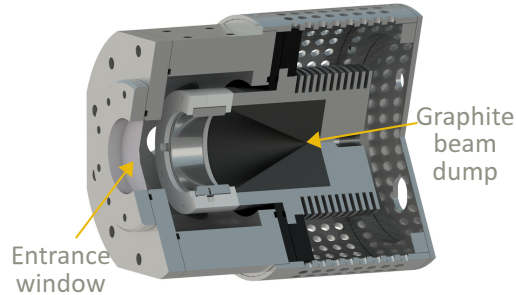
# BEAM DIAGNOSTICS

## --OVERVIEW--



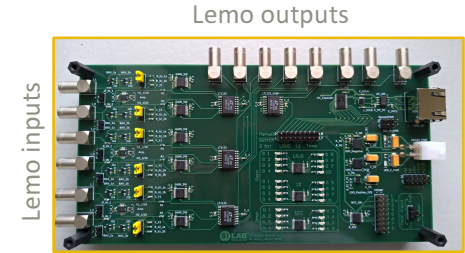
Beam monitor

- Based on secondary electron emission (SEE)
- Two pairs of 5  $\mu\text{m}$  Al-foils, horizontally & vertically segmented
- Beam penetration causes signal  $I_{\text{foil}} \sim I_{\text{beam}}$ 
  - Calibration allows online beam meas.
- Isolated aperture allows direct beam cut-off measurements



Faraday cup (FC)

- Beam current  $I_{\text{beam}}$  measurement by dumping into graphite cone
- Directly obtain current  $I_{\text{FC}} = I_{\text{beam}}$  with low uncertainty
  - $\Delta I_{\text{FC}} / I_{\text{FC}} \leq 1\%$

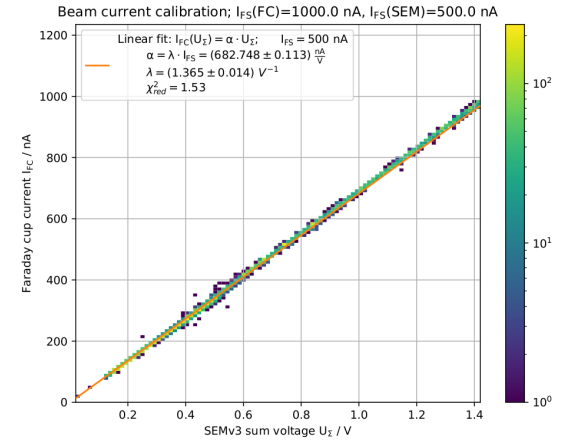
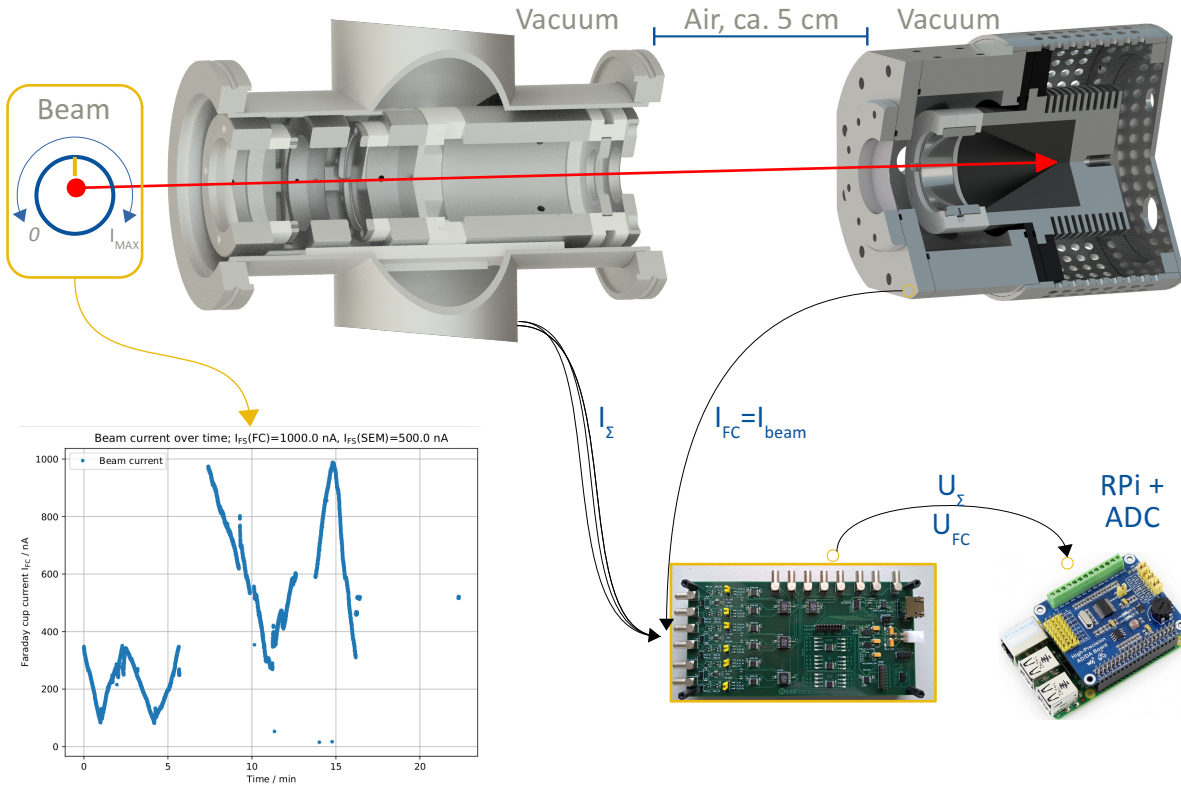


R/O board

- Analog R/O of beam monitor & FC
- Linear mapping of input current  $I$ 
  - $0 - I_{\text{FS}} \rightarrow 0 - 5\text{V}$
- Multiple, switchable scales  $I_{\text{FS}}$
- Used to digitize signals

# BEAM DIAGNOSTICS

## --CALIBRATION--



- Calibration  $I_{beam} = \alpha \cdot U_{\Sigma}$  with  $\alpha = \lambda \cdot I_{FS}$

$$I_{beam}(I_{FS}, U_{\Sigma}) = \lambda \cdot I_{FS} \cdot U_{\Sigma}$$

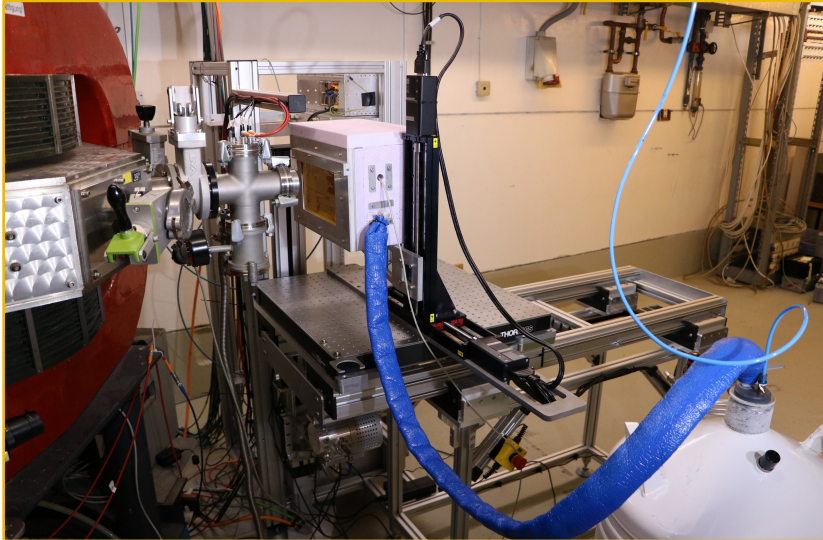
- Uncertainty consideration:

$$\frac{\Delta \lambda}{\lambda} = \frac{\Delta I_{FS}}{I_{FS}} = \frac{\Delta U_{\Sigma}}{U_{\Sigma}} = 1\% \Rightarrow \frac{\Delta I_{beam}}{I_{beam}} = \sqrt{3}\%$$

- Allows online beam current measurement during irradiation

# IRRADIATION

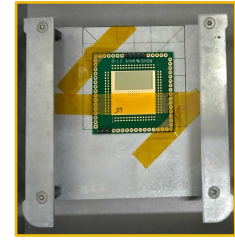
--SITE & TYPICAL DUTs--



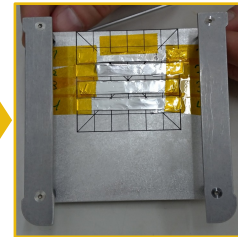
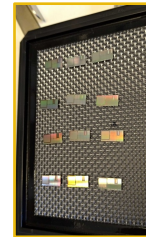
Setup in irradiation position. Liquid nitrogen dewar used to cool down nitrogen gas for cool, dry atmosphere inside box during irradiation



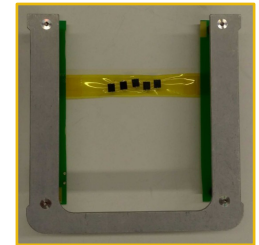
*Assembly on SCC*



*Sensor on surfboard*



*Bare sensors, wrapped in Al-foil*

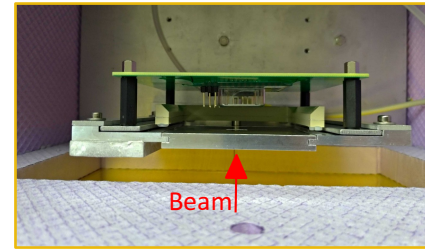


*PiN-diodes on Kapton tape*

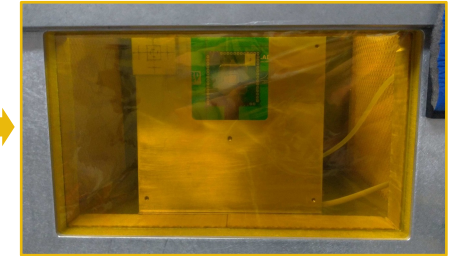
Variety of different DUTs, all mounted on custom-made holder for installation inside box (behind shield if needed)

# IRRADIATION --PROCEDURE--

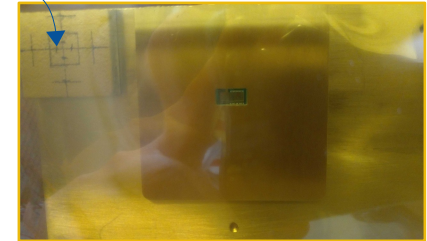
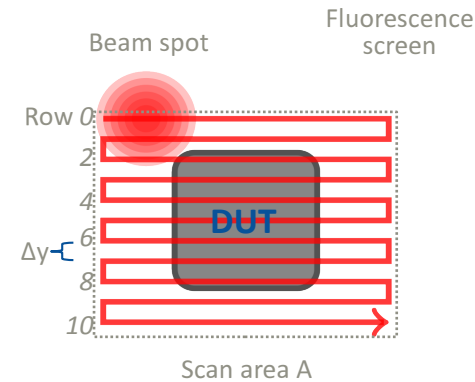
- DUTs mounted behind custom shielding @  $< -20\text{ }^{\circ}\text{C}$ , temp monitoring via NTCs in box
- Beam-based alignment using fluorescence screens, cameras and beam monitor
- Homogeneous irradiation by overscanning DUT area
- Row-wise scanning with row separation  $\Delta y$  and velocity  $v$
- Proton fluence per completed scan ( $v = \text{const.}$  on DUT area)  $\rightarrow \phi_p = \frac{I_{\text{beam}}}{q_e \cdot v \cdot \Delta y}$
- Uncertainty dominated by  $I_{\text{beam}}$   $\rightarrow \frac{\Delta \phi_p}{\phi_p} = \frac{\Delta I_{\text{beam}}}{I_{\text{beam}}} = \sqrt{3\%}$
- Typical values:  $I_{\text{beam}} = 1\mu\text{A}$ ,  $v = 70\text{ mm/s}$ ,  $\Delta y = 1\text{ mm}$ 
  - $\phi_p \approx 1e13\text{ p/cm}^2$  per scan  $\rightarrow 1e16\text{ n}_{\text{eq}}/\text{cm}^2$  in  $\sim 2\text{ h}$



Top view of DUT mounted behind shield



Front view of DUT mounted, w/o custom shield



Front view of DUT mounted, with custom shield. Only DUT cross section sees beam



# IRRADIATION

## --IMPROVING UNCERTAINTY/HOMOGENEITY--

- Pre-irradiation:

- On-the-fly calibration before / after irradiation to maximize calibration precision

- Irradiation:

- **Beam-driven** scan procedure; beam parameters checked for predefined requirements each row
- Allows pausing irradiation for in-between analysis; IV-curves, threshold scan, power up, ...
- Storage of all irradiation-related data for on and offline analysis

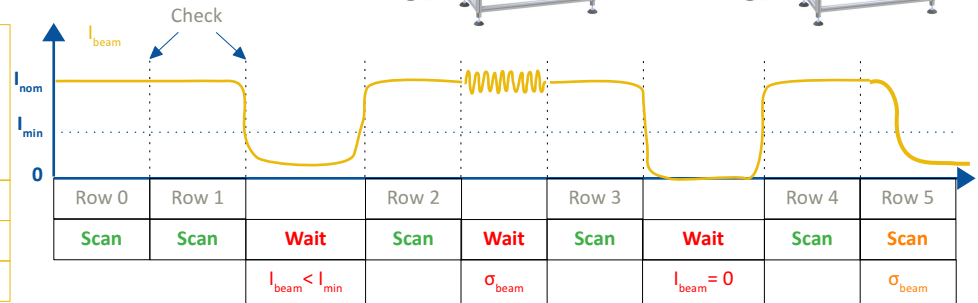
- Post-irradiation:

- Correction of fluence distribution by scanning individual rows  
→ Especially useful for low-fluence scans

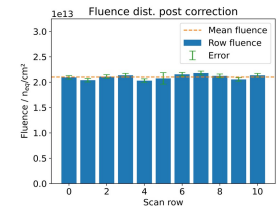
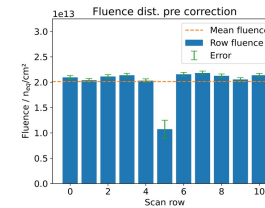
Setup moving from calibration to irradiation position



Beam current, sampled @ up to 100 Hz
Progress
Status
Criteria



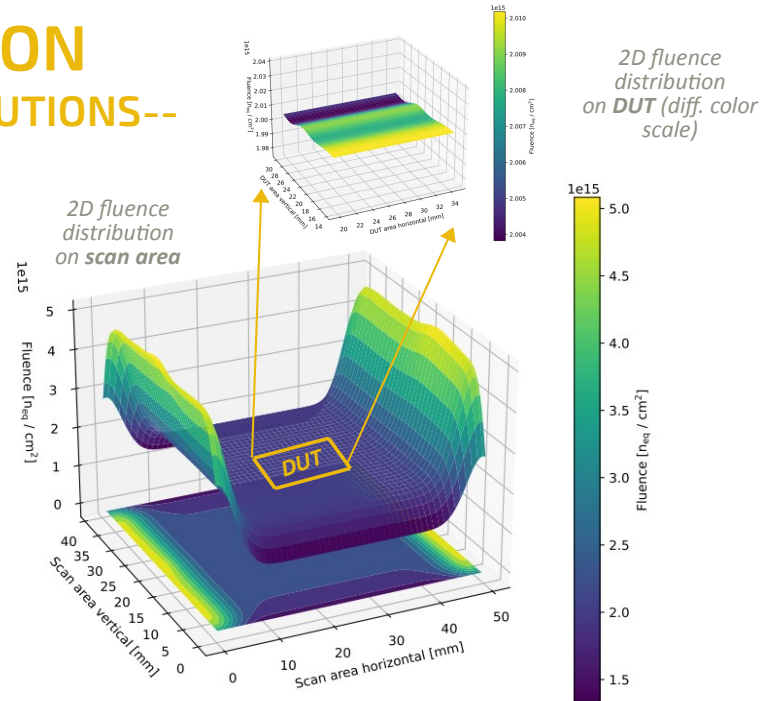
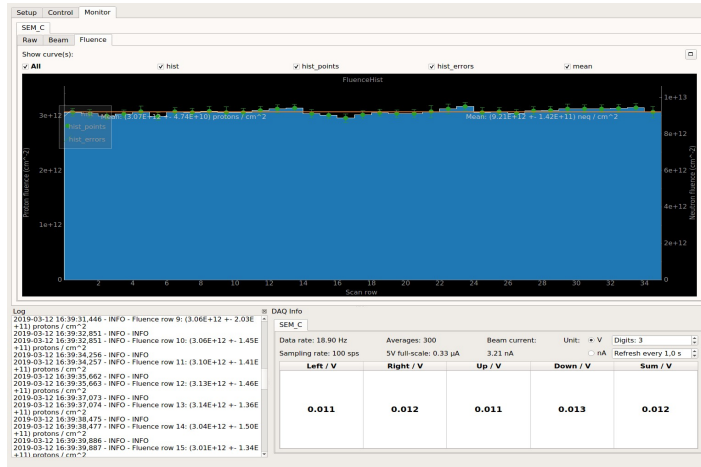
One scan irradiation:  
Beam failure scanning row 5, corrected after scan





# IRRADIATION --FLUENCE DISTRIBUTIONS--

Online fluence monitor of control software

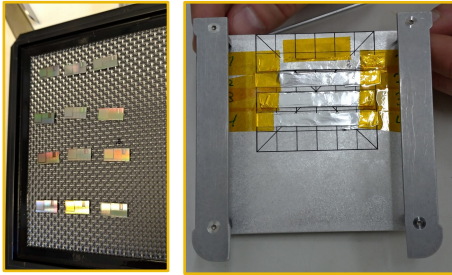


- Online, 1D fluence monitoring of control software
  - › Fluence contribution of each row to overall fluence
  - › Generated by  $\phi_p = \frac{I_{\text{beam}}}{q_e \cdot v \cdot \Delta y}$  for each row, turning points not considered

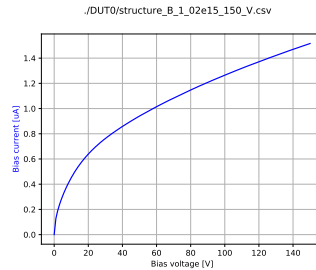
- Offline generated, 2D fluence distribution from raw irradi. data
  - › Reconstruction of fluence distribution over entire scan area, considering turning points → extract 2D fluence dist. on DUT
  - › On- and offline fluence yield same result → nice cross-check

# RADIATION DAMAGE

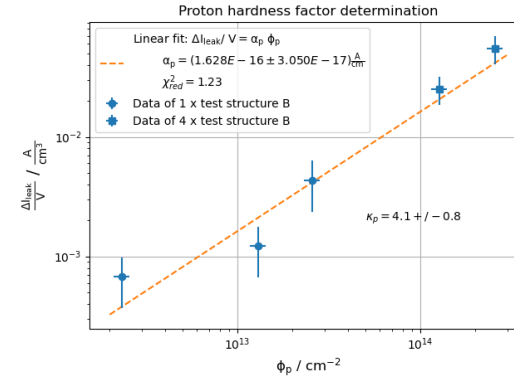
## --LATEST MEASUREMENTS--



Test structures in gel pad and wrapped in 10  $\mu\text{m}$  Al-foil on carrier for irradiation



IV-curve for TS B after  $1\text{e}15 \text{ n}_{\text{eq}}/\text{cm}^2$



- Jun-Aug 2020: irradiation of 200  $\mu\text{m}$  LFoundry test structures (TS)
  - $\{1 \times 1\text{e}13, 1 \times 5\text{e}13, 1 \times 1\text{e}14, 4 \times 5\text{e}14, 4 \times 1\text{e}15\} \text{ n}_{\text{eq}}/\text{cm}^2$
- Std. annealing for 80 min @ 60  $^\circ\text{C}$ , IV meas. in fridge
- Full depletion voltage for leakage measurement taken from †

- Fit of  $\Delta I_{\text{leak}} / V_{\text{dep}} = \alpha_p \cdot \phi_p$ 

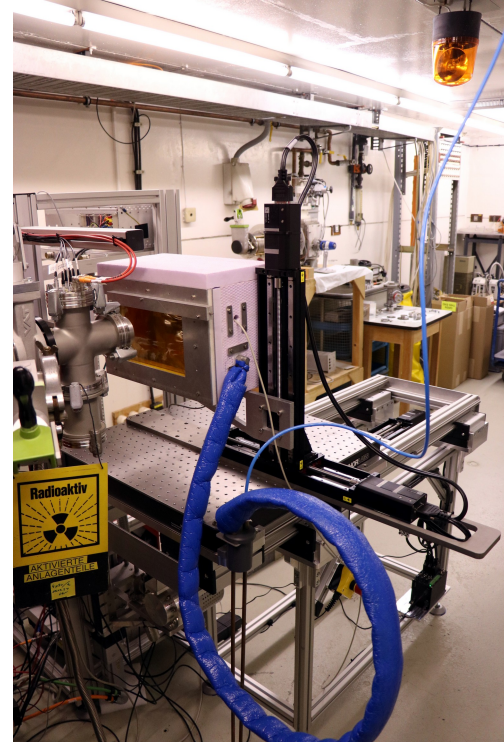
$$\alpha_{\text{eq}} = (3.99 \pm 0.03) \times 10^{-17} \text{ A cm}^{-2}$$

$$\rightarrow \kappa = \alpha_p / \alpha_{\text{neq}} = 4.1 \pm 0.8$$
- In agreement with expectations but large uncertainty
- As of mid 2021: dedicated CV-measurement setup implemented in Bonn
- New irradiations to take place soon reduce uncertainty

† Charge collection properties of irradiated depleted CMOS pixel test structures, I. Mandić

# CONCLUSION & OUTLOOK

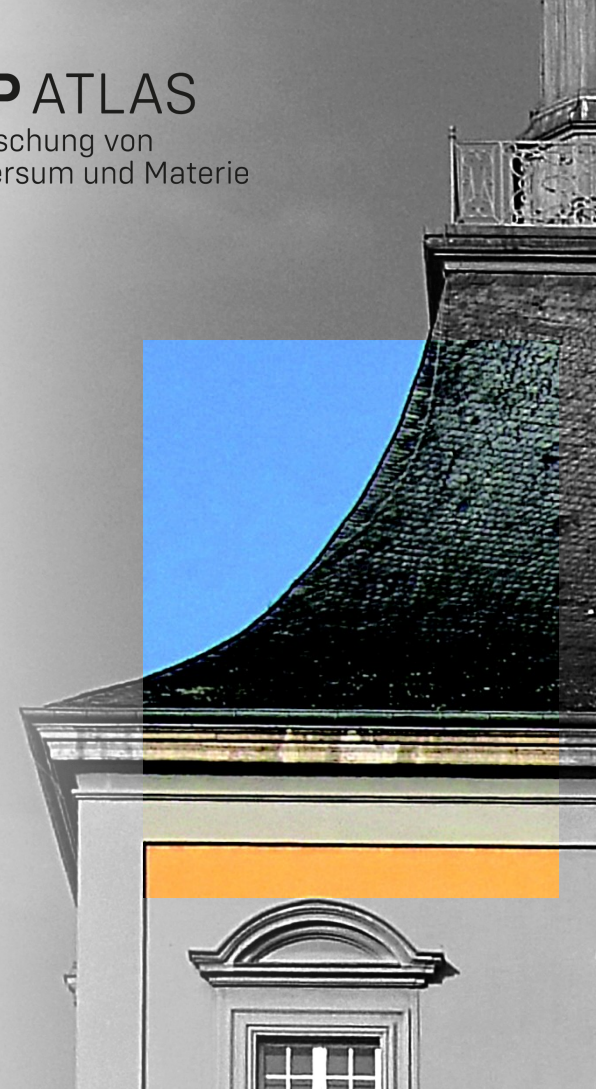
- The proton irradiation site in Bonn allows for optimized proton fluence homogeneity & uncertainty irradiations
- Custom beam monitoring enables beam-driven irradiation procedure with  $\frac{\Delta\phi_p}{\phi_p} \leq 2\%$
- Irradiation datasets allow for extensive analysis e.g fluence distributions
- Latest irradiations of 200  $\mu\text{m}$  thin LF structures yield  $\kappa_p \approx 4$  enabling irradiation of  $1\text{e}16 \text{ n}_{\text{eq}}/\text{cm}^2$  within 2 h, but  $\kappa_p$  main source of uncertainty ( $\Delta\kappa_p/\kappa_p \approx 20\%$ )
- Outlook:
  - Thorough elec. characterization before/after irradiation of thin devices for precise hardness factor meas.
  - Currently Uni Bonn is working on giving access to external groups
  - New developments aiming for providing neutron beam for irradiation based on current setup





**FSP ATLAS**  
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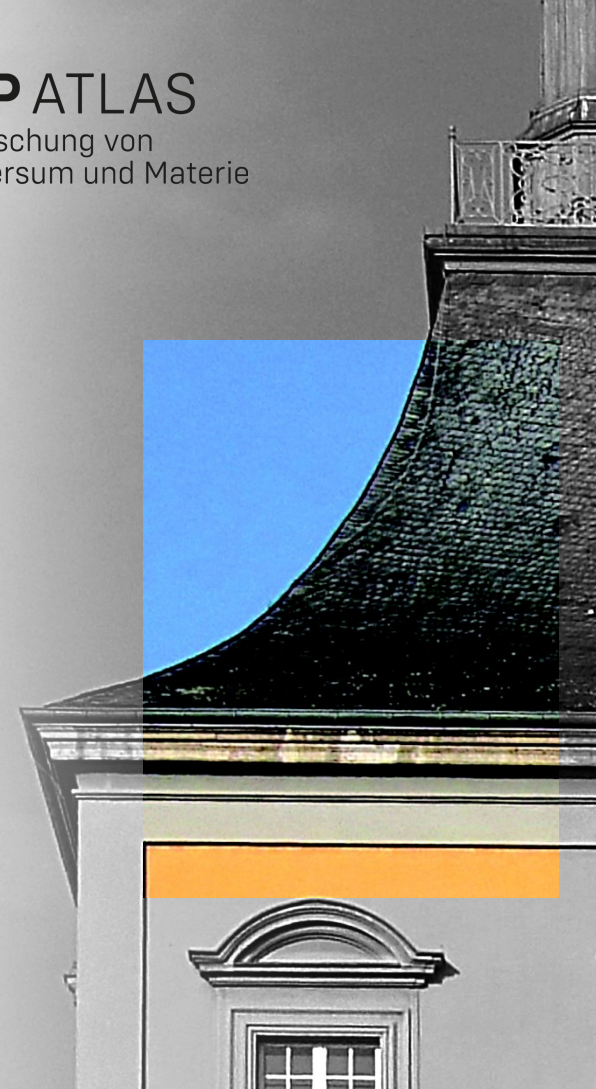
Thank you





**FSP ATLAS**  
Erforschung von  
Universum und Materie

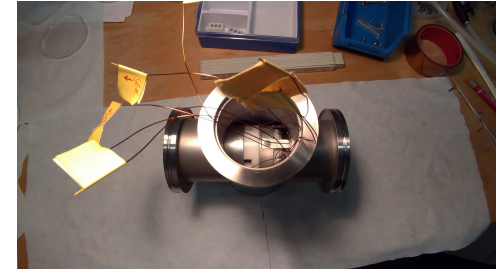
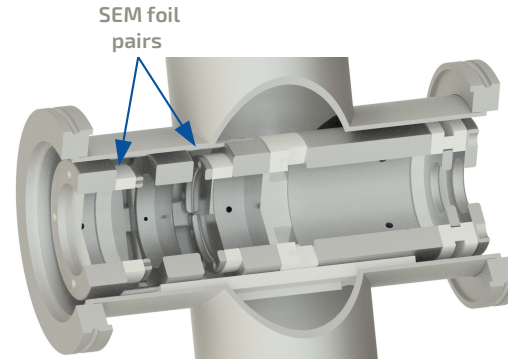
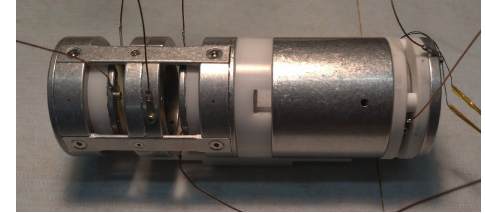
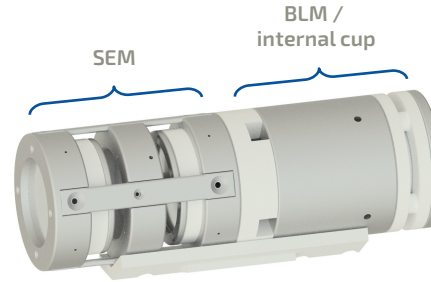
**BACKUP**





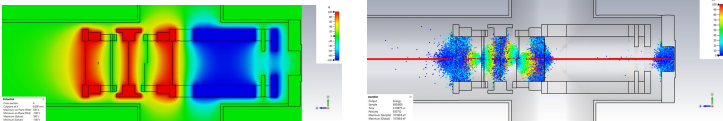
# HARDWARE -Beam Monitor-

- Online beam parameter and cut-off monitoring
- Secondary electron monitor:
  - › 2 C-coated, Al-foil pairs, 3 HV (+100V) foils
- Beam-loss monitor (BLM) / internal cup:
  - › Isolated Al-apertue, HV (-100V) suppressor cylinder / aperture, monitoring NTC
- Fully CST-simulated design:
  - › Electric field distribution
  - › Secondary electron emission and capture
  - › SE capture > 99% @ +/- 100V



CAD render of beam monitor by Dennis Sauerland, 2021

Installation of beam monitor in cross-piece

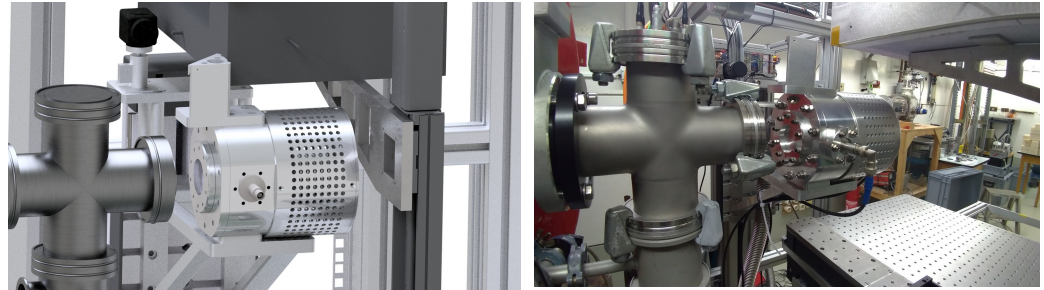
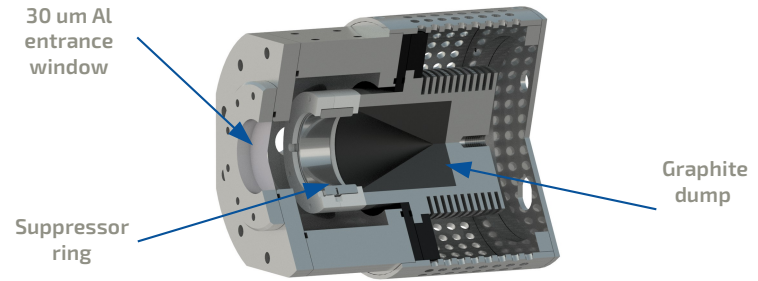




# HARDWARE

## -Faraday Cup with Camera / Screen-

- Absolute beam current measurement after extraction, on-the-fly calibration / adjustment
- Mounted on 700 mm vertical motorstage
- Camera / screen for beam adjustment and profile measurement
- 30 mm entrance window,  $< 1e-6$  mbar, monitoring NTC, suppressor ring (-100V)
- Fully CST-simulated design:
  - Electric field distribution
  - Secondary electron emission and capture
  - SE capture  $> 99\%$  @ -100V

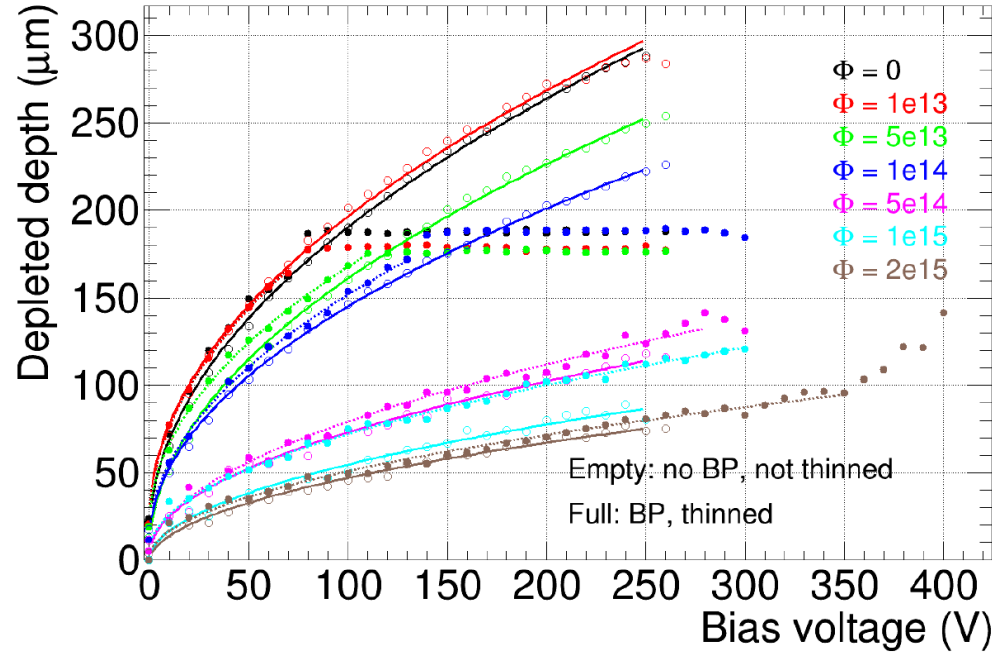


*CAD render of Faraday Cup by Dennis Sauerland, 2021*

*Beam monitor and FC aligned*

# RADIATION DAMAGE

## --PROTON HARDNESS FACTOR--



† Charge collection properties of irradiated depleted CMOS pixel test structures, I. Mandić

# RADIATION DAMAGE

## --LATEST SIMULATIONS--

- 39th RD50 workshop, Valencia Nov 17 2021
- V. Suberts talk: *Non-Ionizing Energy Loss: Geant4 simulations towards more advanced NIEL concept for radiation damage modelling and prediction*
- Agrees with what we expect and measure
  - 12.5 MeV protons  $\rightarrow \kappa_p = 4.04$
- Thanks to Vendula Subert who provided me with her simulation data on short notice!

